	Туре	L :	# Hits	Search Text	DBs	Time Stamp
1	BRS	L1	0	takaishi near massaru.in.	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 11:41
2	BRS	L2	35	takaishi near masaru.in.	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 11:41
3	BRS	L3	5364	((silicon) near3 (thin or film)) near25 ((aluminum) near3 (thin or film))	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 11:42

	Туре	L #	Hits	Search Text	DBs	Time Stamp
4	BRS	L4	273	((silicon) near3 (thin or film)) near25 ((aluminum) near3 (thin or film)) near25 (contact near hole)	; EPO;	2004/12/1 3 11:47
5	BRS	L5	60	near3 (thin or film)) near25 ((aluminum)	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 11:48
6	BRS	L7	24	<pre>(remov\$3 or pattern\$3) near15 ((silicon) near3 (thin or film)) near25 ((aluminum) near3 (thin or film)) near35 (heat\$3)</pre>	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 11 <b>:</b> 49

	Туре	L #	Hits	Search Text	DBs	Time Stamp
7	BRS	L6	804	<pre>(remov\$3 or pattern\$3) near15 ((silicon) near3 (thin or film)) near25 ((aluminum) near3 (thin or film))</pre>	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 12:08
8	BRS	L8	32073	(remov\$3 or pattern\$3) near15 ((silicon)	IF: P() •	2004/12/1 3 12:08
9	BRS	L9	18251	<pre>(remov\$3) near15 ((silicon) near2 (thin or film))</pre>	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 12:10

	Туре	L #	Hits	Search Text	DBs	Time Stamp
10	BRS	L10	25	(remov\$3) near15 ((silicon-containing) near (thin or film))	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 12:09
11	BRS	L12	211	<pre>(remov\$3) near15 ((silicon) near2 (thin or film)) near25 (substrate) same (aluminum)</pre>	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 12:18
12	BRS	L13	866	<pre>(remov\$3) near15 ((silicon) near2 (thin or film)) near25 (substrate) same (contact or hole)</pre>	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 12:18

	Туре	L	#	Hits	Search Text	DBs	Time Stamp
13	BRS	L1	1	5948	<pre>(remov\$3) near15 ((silicon) near2 (thin or film)) near25 (substrate)</pre>	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 15:45
14	BRS	<b>L</b> 1	4	1469	(la or aluminum) near25 (si or silicon) near25 (contact near hole)	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 15:46
15	BRS	L1	5	2254	(al or aluminum) near25 (si or silicon) near25 (contact near hole)	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 15:46

	Туре	L #	Hits	Search Text	DBs	Time Stamp
16	BRS	L16	656	(al or aluminum) near25 (si or silicon) near25 (contact near hole) near25 (substrate)	US- PGPUB ; USPAT ; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 16:18
17	BRS	L17	II ん×っ	(al or aluminum) near25 (si or silicon) near25 (diffus\$3) near25 (substrate)	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 16:19
18	BRS	L19	230	(heat\$3) near15 (al or aluminum) near25 (si or silicon) near25 (diffus\$3) near25 (substrate)	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 16:20

	Туре	L #	Hits	Search Text	DBs	Time Stamp
19	BRS	L18	650	(heat\$3) near15 (al or aluminum) near25 (diffus\$3) near25 (substrate)	US- PGPUB ; USPAT ; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 16:31
20	BRS	L20	1	(heat\$3) near15 (al or aluminum) near3 (thin		2004/12/1 3 16:31
21	BRS	L21	53	(al or aluminum) near3 (thin near film) near25 (diffus\$3) near25 (substrate)	US- PGPUB; USPAT; EPO; JPO; DERWE NT; IBM_T DB	2004/12/1 3 16:32

	บ	1	Document ID	Title	Current OR
1	X			Method for manufacturing semiconductor device and semiconductor device	
2	X		US 20040185660 A1	Method for manufacturing semiconductor device	438/688
3	X		US 20040185659 A1	Method for manufacturing semiconductor device	438/673
4	X		US 6406561 B1	One-step noble metal- aluminide coatings	148/242
5	X		US 4648691 A	Liquid crystal display device having diffusely reflective picture electrode and pleochroic dye	349/162
6	X		US 4177298 A	Method for producing an InSb thin film element	438/547
7	Х		JP 2003051606 A	SUBSTRATE FOR THIN FILM FORMATION	
8	Х		JP 02301132 A	FORMING METHOD FOR ALUMINUM DIFFUSED LAYER ON SEMICONDUCTOR SUBSTRATE	

	U	1	Do	cument ID	Title	Current	OR
9	Х		JP A	02265238	FORMATION OF ALUMINUM SELECTIVE DIFFUSION LAYER ON SILICON SUBSTRATE		
10	X		JP A		SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF		
11	Х		JP A		SOI SUBSTRATE AND MANUFACTURE THEREOF		
12	Х		JP A	60127728	DIFFUSING METHOD OF ALUMINUM TO SEMICONDUCTOR		
13	X		JP A		MANUFACTURE OF SEMICONDUCTOR DEVICE		
14	X		US	3680204 A	Solid state triode - has emitter, collector and control electrodes with body of material supporting emitter space-charge-limi		•